March 2001

## FAIRCHILD

SEMICONDUCTOR TM

## FDT3612

### 100V N-Channel PowerTrench<sup>®</sup> MOSFET

### **General Description**

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers.

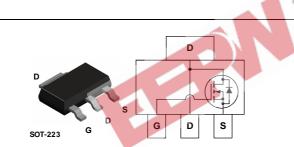
These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable  $R_{\rm DS(ON)}$  specifications. The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power supply designs with higher overall efficiency.

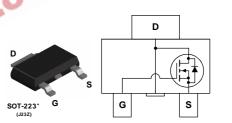
### Applications

- DC/DC converter
- Motor driving

### Features

- 3.7 A, 100 V.  $R_{DS(ON)} = 120 \text{ m}\Omega @ V_{GS} = 10 \text{ V}$  $R_{DS(ON)} = 130 \text{ m}\Omega @ V_{GS} = 6 \text{ V}$
- · Fast switching speed
- Low gate charge (14nC typ)
- High performance trench technology for extremely low R<sub>DS(ON)</sub>
- High power and current handling capability in a widely used surface mount package





### Absolute Maximum Ratings T<sub>A=25°C</sub> unless otherwise noted

Symbol	Parameter			Ratings	Units
V <sub>DSS</sub>	Drain-Sour	ce Voltage		100	V
V <sub>GSS</sub>	Gate-Sourc	e Voltage		±20	V
ID	Drain Curre	ent – Continuous	(Note 1a)	3.7	А
		– Pulsed		20	
PD	Maximum F	ower Dissipation	(Note 1a)	3.0	W
			(Note 1b)	1.3	
			(Note 1c)	1.1	
T <sub>J</sub> , T <sub>STG</sub>	Operating a	and Storage Junction T	emperature Range	-55 to +150	°C
Therma	I Charac	teristics			
R <sub>0JA</sub>	Thermal Re	Thermal Resistance, Junction-to-Ambient (Note 1a)		42	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Note 1)			12	°C/W
Packag	e Markin	g and Orderin	g Information		
Device Marking		Device	Reel Size	Tape width	Quantity
3612		FDT3612	13"	12mm	2500 units

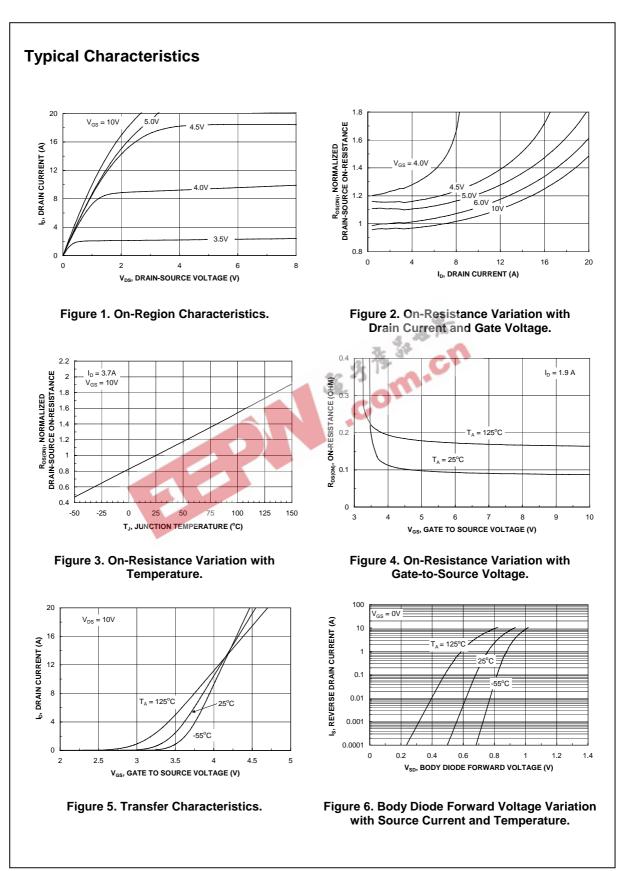
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Irce Avalanche Ratings (Note 2 Drain-Source Avalanche Energy					Units
	<u>2)</u>			L	L
	Single Pulse, $V_{DD} = 50 \text{ V}$ , $I_D = 3.7 \text{ A}$			90	mJ
Drain-Source Avalanche Current				3.7	Α
cteristics					
	$V_{CS} = 0 V$ , $I_{D} = 250 \mu A$	100			V
Breakdown Voltage Temperature	$I_D = 250 \ \mu\text{A}$ , Referenced to 25°C		106		mV/°C
	$V_{DS} = 80 V$ , $V_{GS} = 0 V$			10	μA
Gate–Body Leakage, Forward				100	nA
Gate–Body Leakage, Reverse				-100	nA
		L			L
	$V_{ro} = V_{ro}$ $ r = 250 \mu$	2	25	4	V
0		2	-	4	
Temperature Coefficient	$\mu$ = 200 $\mu$ A, Referenced to 20 C	R-	-6		mV/°C
Static Drain–Source	$V_{GS} = 10 \text{ V}, \qquad I_D = 3.7 \text{ A}$	114	88	120	mΩ
Jn-Resistance		-2-			
On-State Drain Current		10	170	240	A
		10	11		S
					Ũ
		1		1	_
					pF
	f = 1.0  MHz		-		pF
Reverse Transfer Capacitance			20		pF
Characteristics (Note 2)	1	1		1	1
	$V_{DD} = 50 V, I_D = 1 A,$		8.5	17	ns
	$V_{GS} = 10 \text{ V},  R_{GEN} = 6 \Omega$		2	4	ns
			23	37	ns
Гurn–Off Fall Time			4.5	9	ns
Total Gate Charge	$V_{DS} = 50 \text{ V}, \qquad I_D = 3.7 \text{ A},$		14	20	nC
Sate–Source Charge	$V_{GS} = 10$ V		2.4		nC
Gate–Drain Charge			3.8		nC
urce Diode Characteristics a	and Maximum Ratings				
Maximum Continuous Drain–Source	Diode Forward Current			2.5	Α
Drain–Source Diode Forward Voltage	$V_{GS} = 0 V$ , $I_S = 2.5 A$ (Note 2)		0.75	1.2	V
	Drain-Source Breakdown Voltage   Breakdown Voltage Temperature   Coefficient   Zero Gate Voltage Drain Current   Gate-Body Leakage, Forward   Gate-Body Leakage, Reverse   Cteristics (Note 2)   Gate Threshold Voltage   Comperature Coefficient   Static Drain-Source   Dn-State Drain Current   Forward Transconductance   Characteristics   Dutput Capacitance   Dutput Capacitance   Curn-On Delay Time   Turn-On Rise Time   Turn-Off Delay Time   Turn-Off Fall Time   Total Gate Charge   Gate-Source Charge   Gate-Drain Charge   Tree Diode Characteristics at   Maximum Continuous Drain-Source	Drain-Source Breakdown Voltage $V_{GS} = 0 \text{ V}, I_D = 250 \ \mu\text{A}$ Breakdown Voltage Temperature Coefficient $I_D = 250 \ \mu\text{A}, \text{Referenced to } 25^{\circ}\text{C}$ Zero Gate Voltage Drain Current $V_{DS} = 80 \text{ V}, V_{CS} = 0 \text{ V}$ Gate-Body Leakage, Forward $V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage, Reverse $V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage, Reverse $V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage, Reverse $V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage, Reverse $V_{DS} = V_{GS}, I_D = 250 \ \mu\text{A}$ Gate Threshold Voltage $I_D = 250 \ \mu\text{A}, Referenced to } 25^{\circ}\text{C}$ Gate Threshold Voltage $V_{DS} = V_{GS}, I_D = 250 \ \mu\text{A}$ Gate Threshold Voltage $V_{DS} = 10 \text{ V}, I_D = 3.7 \text{ A}$ On-Resistance $V_{GS} = 10 \text{ V}, I_D = 3.7 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 3.7 \text{ A}$ $V_{GS} = 10 \text{ V}, V_{DS} = 10 \text{ V}$ Forward Transconductance $V_{DS} = 10 \text{ V}, V_{DS} = 10 \text{ V}$ On-State Drain Current $V_{DS} = 50 \text{ V}, V_{CS} = 0 \text{ V}, I_D = 3.7 \text{ A}$ Characteristics $V_{DS} = 50 \text{ V}, I_D = 3.7 \text{ A}$ Duptut Capacitance $V_{DS} = 50 \text{ V}, I_D = 1 \text{ A}, V_{GS} = 10 \text{ V}$ Curn-On Delay Time $V_{DS} = 50 \text{ V}, I_D = 3.7 \text{ A}, V_{GS} = 10 \text{ V}$ Turn-On Rise Time $V_{DS} = 50 \text{ V}, I_D = 3.7 \text{ A}, V_{GS} = 10 \text{ V}$ Turn-Off Delay Time $V_{DS} = 50 \text{ V}, I_D = 3.7 \text{ A}, V_{GS} = 10 \text{ V}$ Gate-Source Charge $V_{DS} = 50 \text{ V}, I_D = 3.7 \text{ A}, V_{GS} = 10 \text{ V}$ Gate-Drain Charge $V_{DS} = 50 \text{ V}, I_D = 3.7 $	Drain–Source Breakdown Voltage $V_{GS} = 0 V, I_D = 250 \mu A$ 100Breakdown Voltage Temperature Coefficient $I_D = 250 \mu A$ , Referenced to $25^{\circ}C$ 100Breakdown Voltage Drain Current $V_{DS} = 80 V, V_{GS} = 0 V$ 100Sate–Body Leakage, Forward $V_{GS} = 20 V, V_{DS} = 0 V$ 100Sate–Body Leakage, Reverse $V_{GS} = -20 V, V_{DS} = 0 V$ 100Sate–Body Leakage, Reverse $V_{GS} = -20 V, V_{DS} = 0 V$ 100Sate–Body Leakage, Reverse $V_{GS} = -20 V, V_{DS} = 0 V$ 100Sate Threshold Voltage $I_D = 250 \mu A$ 2Sate Threshold Voltage $I_D = 250 \mu A$ , Referenced to $25^{\circ}C$ 100Sate Threshold Voltage $I_D = 3.7 A$ 2Sate Transconductance $V_{GS} = 10 V, I_D = 3.7 A$ 100On–State Drain Current $V_{GS} = 10 V, I_D = 3.7 A$ 100Sorward Transconductance $V_{DS} = 10 V, I_D = 3.7 A$ 100CharacteristicsNume $V_{DS} = 50 V, V_{GS} = 0 V, f = 1.0 MHz$ 100Severse Transfer Capacitance $V_{DS} = 50 V, I_D = 1 A, V_{GS} = 0 V, f = 1.0 MHz$ 100Curn–On Delay Time $V_{DS} = 50 V, I_D = 1 A, V_{GS} = 10 V, R_{GEN} = 6 \Omega$ 100Sate–Drain Charge $V_{DS} = 50 V, I_D = 3.7 A, V_{GS} = 10 V, V_{GS} = 10 V, V_{GS} = 10 V, V_{GS} = 10 V, R_{GEN} = 6 \Omega$ 100Sate–Charge $V_{DS} = 50 V, I_D = 3.7 A, V_{GS} = 10 V, R_{GEN} = 6 \Omega$ 100Sate–Drain Charge $V_{DS} = 50 V, I_D = 3.7 A, V_{GS} = 10 V, R_{GEN} = 6 \Omega$ 100Sate–Drain Charge $V_{DS} = 50 V, I_D = 3.7 A, V_{GS} = 10 V, R_{GEN} = 6 \Omega$ <t< td=""><td><math display="block">\begin{array}{c c c c c c c } \hline V_{GS} = 0 \ V, \ I_D = 250 \ \mu A &amp; 100 \\ \hline I_D = 250 \ \mu A, \ Referenced \ to \ 25^\circ C &amp; 106 \\ \hline I_D = 250 \ \mu A, \ Referenced \ to \ 25^\circ C &amp; 106 \\ \hline I_D = 250 \ \mu A, \ Referenced \ to \ 25^\circ C &amp; 106 \\ \hline I_D = 250 \ \mu A, \ Referenced \ to \ 25^\circ C &amp; 106 \\ \hline I_D = 250 \ \mu A, \ Referenced \ to \ 25^\circ C &amp; 106 \\ \hline I_D = 250 \ \mu A, \ Referenced \ to \ 25^\circ C &amp; 106 \\ \hline I_D = 250 \ \mu A, \ Referenced \ to \ 25^\circ C &amp; 106 \\ \hline I_D = 250 \ \mu A, \ Referenced \ to \ 25^\circ C &amp; 106 \\ \hline I_D = 250 \ \mu A, \ Referenced \ to \ 25^\circ C &amp; -6 \\ \hline I_D = 250 \ \mu A, \ Referenced \ to \ 25^\circ C &amp; -6 \\ \hline I_D = 250 \ \mu A, \ Referenced \ to \ 25^\circ C &amp; -6 \\ \hline I_D = 250 \ \mu A, \ Referenced \ to \ 25^\circ C &amp; -6 \\ \hline I_D = 250 \ \mu A, \ Referenced \ to \ 25^\circ C &amp; -6 \\ \hline I_D = 250 \ \mu A, \ Referenced \ to \ 25^\circ C &amp; -6 \\ \hline I_D = 250 \ \mu A, \ Referenced \ to \ 25^\circ C &amp; 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2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%

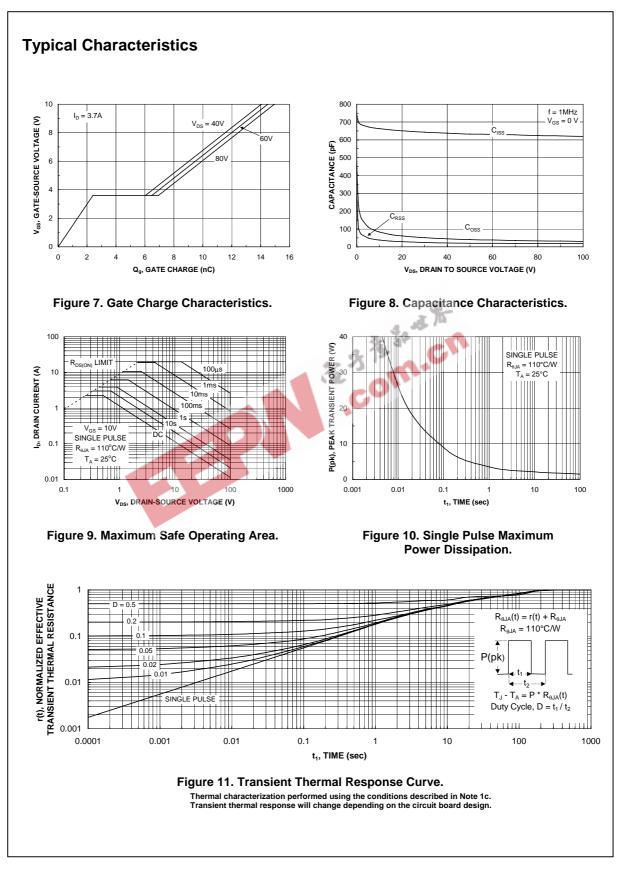
FDT3612 Rev. C1 (W)

# FDT3612



## FDT3612

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FDT3612

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